

<b>Notice of References Cited</b>	Application/Control No. 10/049,570	Applicant(s)/Patent Under Reexamination TAKAHASHI ET AL.	
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**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-2003/0159178	08-2003	Ulvskov et al	---
	B	US-			
	C	US-			
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

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	N	WO 99/03892	01-1999	WO	---	---
	O	WO 97/49298	12-1997	WO	---	---
	P					
	Q					
	R					
	S					
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**NON-PATENT DOCUMENTS**

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